

Search Notes

Application/Control No.

10/559,846

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

IGARASHI ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	66	10/07	hnh
439	91	↓	↓
439	86	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR